Product Preview

# Quad Analog Switch/ Multiplexer/Demultiplexer with Separate Analog and Digital Power Supplies

**High-Performance Silicon-Gate CMOS** 

The MC74HC4316A utilizes silicon–gate CMOS technology to achieve fast propagation delays, low ON resistances, and low OFF–channel leakage current. This bilateral switch/multiplexer/demultiplexer controls analog and digital voltages that may vary across the full analog power–supply range (from  $V_{CC}$  to  $V_{EE}$ ).

The HC4316A is similar in function to the metal–gate CMOS MC14016 and MC14066, and to the High–Speed CMOS HC4066A. Each device has four independent switches. The device control and Enable inputs are compatible with standard CMOS outputs; with pullup resistors, they are compatible with LSTTL outputs. The device has been designed so that the ON resistances (RON) are much more linear over input voltage than RON of metal–gate CMOS analog switches. Logic–level translators are provided so that the On/Off Control and Enable logic–level voltages need only be VCC and GND, while the switch is passing signals ranging between VCC and VEE. When the Enable pin (active–low) is high, all four analog switches are turned off.

- Logic-Level Translator for On/Off Control and Enable Inputs
- Fast Switching and Propagation Speeds
- High ON/OFF Output Voltage Ratio
- Diode Protection on All Inputs/Outputs
- Analog Power–Supply Voltage Range (V<sub>CC</sub> V<sub>EE</sub>) = 2.0 to 12.0 Volts
- Digital (Control) Power–Supply Voltage Range (V<sub>CC</sub> GND) = 2.0 to 6.0 Volts, Independent of V<sub>EE</sub>
- Improved Linearity of ON Resistance
- Chip Complexity: 66 FETs or 16.5 Equivalent Gates

10 X<sub>C</sub>

9 | V<sub>EE</sub>

#### 

ENABLE I

GND

**PIN ASSIGNMENT** 

# **FUNCTION TABLE**

Inp	State of						
Enable	On/Off Control	Analog Switch					
L	Н	On					
L	L	Off					
Н	Off						
X = don't care							

This document contains information on a product under development. ON Semiconductor reserves the right to change or discontinue this product without notice.



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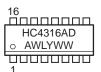


PDIP-16 N SUFFIX CASE 648





SOIC-16 D SUFFIX CASE 751B





TSSOP-16 DT SUFFIX CASE 948F





SOEIAJ-16 F SUFFIX CASE 966



A = Assembly Location

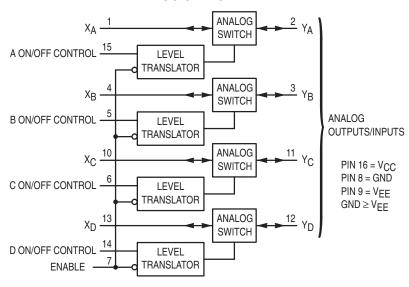
WL or L = Wafer Lot YY or Y = Year WW or W = Work Week

## ORDERING INFORMATION

Device	Package	Shipping					
MC74HC4316AN	PDIP-16	2000 / Box					
MC74HC4316AD	SOIC-16	48 / Rail					
MC74HC4316ADR2	SOIC-16	2500 / Reel					
MC74HC4316ADT	TSSOP-16	96 / Rail					
MC74HC4316ADTR2	TSSOP-16	2500 / Reel					
MC74HC4316AF	SOEIAJ-14	See Note 1.					

 For ordering information on the EIAJ version of the SOIC packages, please contact your local ON Semiconductor representative.

#### **LOGIC DIAGRAM**



ANALOG INPUTS/OUTPUTS =  $X_A$ ,  $X_B$ ,  $X_C$ ,  $X_D$ 

#### **MAXIMUM RATINGS\***

Symbol	Parameter	Value	Unit	
VCC	Positive DC Supply Voltage	(Ref. to GND) (Ref. to VEE)	- 0.5 to + 7.0 - 0.5 to + 14.0	>
VEE	Negative DC Supply Voltage (Ref. to	GND)	- 7.0 to + 0.5	V
VIS	Analog Input Voltage		VEE - 0.5 to V <sub>CC</sub> + 0.5	>
V <sub>in</sub>	DC Input Voltage (Ref. to GND)		- 0.5 to V <sub>CC</sub> + 0.5	V
I	DC Current Into or Out of Any Pin		± 25	mA
P <sub>D</sub>		Plastic DIP† SOIC Package† SOP Package†	750 500 450	mW
T <sub>stg</sub>	Storage Temperature		- 65 to + 150	°C
TL	Lead Temperature, 1 mm from Case (Plastic DIP, SOIC or TS		260	°C

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high–impedance circuit. For proper operation,  $V_{in}$  and  $V_{out}$  should be constrained to the range GND  $\leq$  ( $V_{in}$  or  $V_{out}$ )  $\leq$   $V_{CC}$ .

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V<sub>CC</sub>). Unused outputs must be left open. I/O pins must be connected to a properly terminated line or bus.

For high frequency or heavy load considerations, see Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

<sup>\*</sup>Maximum Ratings are those values beyond which damage to the device may occur.

Functional operation should be restricted to the Recommended Operating Conditions.

<sup>†</sup>Derating — Plastic DIP: – 10 mW/°C from 65° to 125°C

EIAJ/SOIC Package: - 7 mW/°C from 65° to 125°C

TSSOP Package: - 6.1 mW/°C from 65° to 125°C

#### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter		Min	Max	Unit
VCC	Positive DC Supply Voltage (Ref. to 0	GND)	2.0	6.0	V
VEE	Negative DC Supply Voltage (Ref. to	GND)	-6.0	GND	V
VIS	Analog Input Voltage			Vcc	V
V <sub>in</sub>	Digital Input Voltage (Ref. to GND)	GND	Vcc	V	
V <sub>IO</sub> *	Static or Dynamic Voltage Across Sw	vitch	_	1.2	V
TA	Operating Temperature, All Package	Types	- 55	+ 125	°C
t <sub>r</sub> , t <sub>f</sub>	Input Rise and Fall Time (Control or Enable Inputs) (Figure 10)	V <sub>CC</sub> = 2.0 V V <sub>CC</sub> = 3.0 V V <sub>CC</sub> = 4.5 V V <sub>CC</sub> = 6.0 V	0 0 0	1000 600 500 400	ns

<sup>\*</sup>For voltage drops across the switch greater than 1.2 V (switch on), excessive V<sub>CC</sub> current may be drawn; i.e., the current out of the switch may contain both V<sub>CC</sub> and switch input components. The reliability of the device will be unaffected unless the Maximum Ratings are exceeded.

# DC ELECTRICAL CHARACTERISTICS Digital Section (Voltages Referenced to GND) VEE = GND Except Where Noted

					Gu	aranteed Li	mit	
Symbol	Parameter	Test Conditi	ions	V <sub>CC</sub>	– 55 to 25°C	≤ 85°C	≤ 125°C	Unit
VIH	Minimum High–Level Voltage, Control or Enable Inputs	R <sub>on</sub> = Per Spec		2.0 3.0 4.5 6.0	1.5 2.1 3.15 4.2	1.5 2.1 3.15 4.2	1.5 2.1 3.15 4.2	V
VIL	Maximum Low-Level Voltage, Control or Enable Inputs	R <sub>on</sub> = Per Spec		2.0 3.0 4.5 6.0	0.5 0.9 1.35 1.8	0.5 0.9 1.35 1.8	0.5 0.9 1.35 1.8	V
l <sub>in</sub>	Maximum Input Leakage Current, Control or Enable Inputs	V <sub>in</sub> = V <sub>CC</sub> or GND V <sub>EE</sub> = -6.0 V		6.0	± 0.1	± 1.0	± 1.0	μΑ
Icc	Maximum Quiescent Supply Current (per Package)	$V_{\text{in}} = V_{\text{CC}} \text{ or GND}$ $V_{\text{IO}} = 0 \text{ V}$	V <sub>EE</sub> = GND V <sub>EE</sub> = -6.0	6.0 6.0	2 4	20 40	40 160	μΑ

NOTE: Information on typical parametric values can be found in Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

#### DC ELECTRICAL CHARACTERISTICS Analog Section (Voltages Referenced to VFF)

					Gu	aranteed Li	mit	
Symbol	Parameter	Test Conditions	V <sub>CC</sub>	V <sub>EE</sub> V	– 55 to 25°C	≤ 85°C	≤ 125°C	Unit
R <sub>on</sub>	Maximum "ON" Resistance	$V_{\text{IN}} = V_{\text{IH}}$ $V_{\text{IS}} = V_{\text{CC}}$ to $V_{\text{EE}}$ $I_{\text{S}} \le 2.0 \text{ mA (Figures 1, 2)}$	2.0* 4 5 4.5 6.0	0.0 0.0 - 4.5 - 6.0	— 160 90 90	 200 110 110		Ω
		$V_{\text{in}} = V_{\text{IH}}$ $V_{\text{IS}} = V_{\text{CC}}$ or $V_{\text{EE}}$ (Endpoints) $I_{\text{S}} \le 2.0 \text{ mA}$ (Figures 1, 2)	2.0 4.5 4.5 6.0	0.0 0.0 - 4.5 - 6.0	— 90 70 70	— 115 90 90	— 140 105 105	
ΔR <sub>on</sub>	Maximum Difference in "ON" Resistance Between Any Two Channels in the Same Package	$\begin{aligned} & \forall_{\text{IN}} = \forall_{\text{IH}} \\ & \forall_{\text{IS}} = 1/2 \left( \forall_{\text{CC}} - \forall_{\text{EE}} \right) \\ & \exists_{\text{S}} \leq 2.0 \text{ mA} \end{aligned}$	2.0 4.5 4.5 6.0	0.0 0.0 -4.5 -6.0	 20 15 15	 25 20 20	— 30 25 25	Ω
l <sub>off</sub>	Maximum Off–Channel Leakage Current, Any One Channel	V <sub>IO</sub> = V <sub>IL</sub> V <sub>IO</sub> = V <sub>CC</sub> or V <sub>EE</sub> Switch Off (Figure 3)	6.0	-6.0	0.1	0.5	1.0	μА
lon	Maximum On–Channel Leakage Current, Any One Channel	V <sub>in</sub> = V <sub>IH</sub> V <sub>IS</sub> = V <sub>CC</sub> or V <sub>EE</sub> (Figure 4)	6.0	-6.0	0.1	0.5	1.0	μА

<sup>\*</sup>At supply voltage (V<sub>CC</sub> – V<sub>EE</sub>) approaching 2 V the analog switch–on resistance becomes extremely non–linear. Therefore, for low–voltage operation, it is recommended that these devices only be used to control digital signals.

# AC ELECTRICAL CHARACTERISTICS ( $C_L$ = 50 pF, Control or Enable $t_f$ = $t_f$ = 6 ns, $V_{EE}$ = GND)

			Gu	aranteed Li	mit	
Symbol	Parameter	v <sub>CC</sub>	– 55 to 25°C	≤ 85°C	≤ 125°C	Unit
tPLH, tPHL	Maximum Propagation Delay, Analog Input to Analog Output (Figures 8 and 9)		40 6 5	50 8 7	60 9 8	ns
tPLZ, tPHZ	Maximum Propagation Delay, Control or Enable to Analog Output (Figures 10 and 11)		130 40 30	160 50 40	200 60 50	ns
t <sub>PZL</sub> , t <sub>PZH</sub>	Maximum Propagation Delay, Control or Enable to Analog Output (Figures 10 and 11)		140 40 30	175 50 40	250 60 50	ns
С	Maximum Capacitance ON/OFF Control and Enable Inputs	_	10	10	10	pF
	Control Input = GND Analog I/O Feedthrough	_ _	35 1.0	35 1.0	35 1.0	

## NOTES:

<sup>2.</sup> Information on typical parametric values can be found in Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

		Typical @ 25°C, V <sub>CC</sub> = 5.0 V	
C <sub>PD</sub>	Power Dissipation Capacitance (Per Switch) (Figure 13)*	15	pF

<sup>\*</sup> Used to determine the no–load dynamic power consumption: PD = CPD VCC<sup>2</sup>f + ICC VCC. For load considerations, see Chapter 2 of the ON Semiconductor High–Speed CMOS Data Book (DL129/D).

NOTE: Information on typical parametric values can be found in Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

<sup>1.</sup> For propagation delays with loads other than 50 pF, see Chapter 2 of the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

# **ADDITIONAL APPLICATION CHARACTERISTICS** (GND = 0 V)

Symbol	Parameter	Test Conditions	V <sub>CC</sub>	V <sub>EE</sub> V	Limit* 25°C	Unit
BW	Maximum On–Channel Bandwidth or Minimum Frequency Response (Figure 5)	$\begin{array}{l} f_{in} = 1 \text{ MHz Sine Wave} \\ \text{Adjust } f_{in} \text{ Voltage to Obtain 0 dBm at V}_{OS} \\ \text{Increase } f_{in} \text{ Frequency Until dB Meter} \\ \text{Reads} - 3 \text{ dB} \\ \text{RL} = 50 \ \Omega, \ C_L = 10 \ pF \end{array}$	2.25 4.50 6.00	- 2.25 - 4.50 - 6.00	150 160 160	MHz
_	Off-Channel Feedthrough Isolation (Figure 6)	$ \begin{aligned} f_{in} &\equiv \text{Sine Wave} \\ \text{Adjust } f_{in} &\text{ Voltage to Obtain 0 dBm at V}_{IS} \\ f_{in} &= 10 \text{ kHz, R}_{L} = 600 \ \Omega, C_{L} = 50 \text{ pF} \end{aligned} $	2.25 4.50 6.00	- 2.25 - 4.50 - 6.00	- 50 - 50 - 50	dB
		$f_{in}$ = 1.0 MHz, $R_L$ = 50 $\Omega$ , $C_L$ = 10 pF	2.25 4.50 6.00	- 2.25 - 4.50 - 6.00	- 40 - 40 - 40	
_	Feedthrough Noise, Control to Switch (Figure 7)	$V_{in} \leq$ 1 MHz Square Wave ( $t_r$ = $t_f$ = 6 ns) Adjust R <sub>L</sub> at Setup so that I <sub>S</sub> = 0 A R <sub>L</sub> = 600 $\Omega$ , C <sub>L</sub> = 50 pF	2.25 4.50 6.00	- 2.25 - 4.50 - 6.00	60 130 200	mVpp
		$R_L = 10 \text{ k}\Omega$ , $C_L = 10 \text{ pF}$	2.25 4.50 6.00	- 2.25 - 4.50 - 6.00	30 65 100	
_	Crosstalk Between Any Two Switches (Figure 12)	$ \begin{aligned} f_{in} &\equiv \text{Sine Wave} \\ \text{Adjust } f_{in} &\text{ Voltage to Obtain 0 dBm at V}_{IS} \\ f_{in} &= 10 \text{ kHz, R}_{L} = 600 \ \Omega, C_{L} = 50 \text{ pF} \end{aligned} $	2.25 4.50 6.00	- 2.25 - 4.50 - 6.00	- 70 - 70 - 70	dB
		$f_{in}$ = 1.0 MHz, $R_L$ = 50 $\Omega$ , $C_L$ = 10 pF	2.25 4.50 6.00	- 2.25 - 4.50 - 6.00	- 80 - 80 - 80	
THD	Total Harmonic Distortion (Figure 14)	$\begin{aligned} f_{\text{in}} = 1 \text{ kHz, } R_L = 10 \text{ k}\Omega, & C_L = 50 \text{ pF} \\ \text{THD} = \text{THD}_{\text{Measured}} - \text{THD}_{\text{Source}} \\ & \text{V}_{\text{IS}} = 4.0 \text{ Vpp sine wave} \\ & \text{V}_{\text{IS}} = 8.0 \text{ Vpp sine wave} \\ & \text{V}_{\text{IS}} = 11.0 \text{ Vpp sine wave} \end{aligned}$	2.25 4.50 6.00	- 2.25 - 4.50 - 6.00	0.10 0.06 0.04	%

<sup>\*</sup>Limits not tested. Determined by design and verified by qualification.

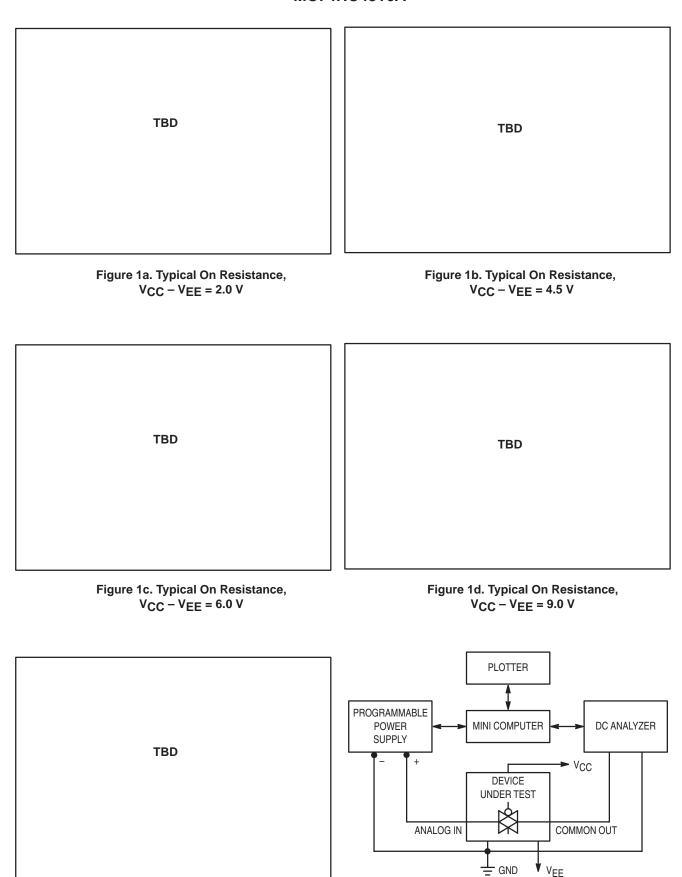


Figure 1e. Typical On Resistance,  $V_{CC} - V_{EE} = 12.0 \text{ V}$ 

Figure 2. On Resistance Test Set-Up

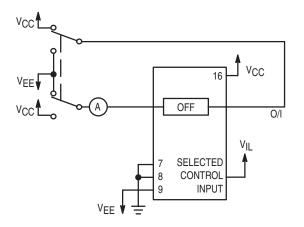


Figure 3. Maximum Off Channel Leakage Current, Any One Channel, Test Set-Up

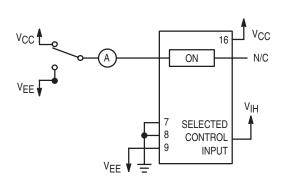
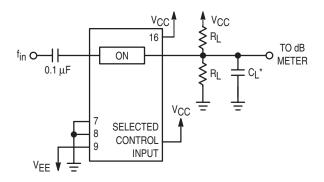
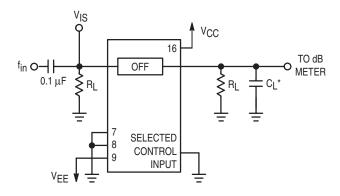


Figure 4. Maximum On Channel Leakage Current, Test Set-Up



<sup>\*</sup>Includes all probe and jig capacitance.

Figure 5. Maximum On-Channel Bandwidth Test Set-Up



\*Includes all probe and jig capacitance.

Figure 6. Off-Channel Feedthrough Isolation, Test Set-Up

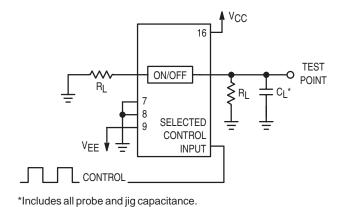


Figure 7. Feedthrough Noise, Control to Analog Out, Test Set-Up

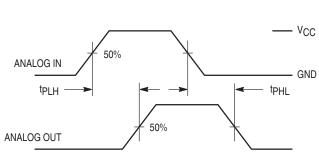
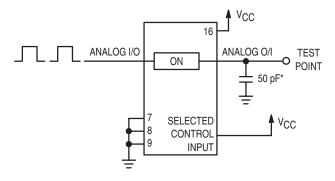
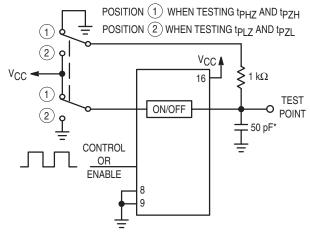


Figure 8. Propagation Delays, Analog In to Analog Out



\*Includes all probe and jig capacitance.

Figure 9. Propagation Delay Test Set-Up



\*Includes all probe and jig capacitance.

Figure 11. Propagation Delay Test Set-Up

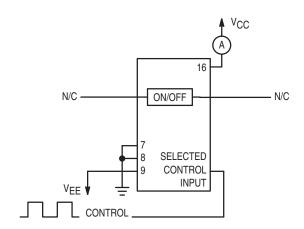


Figure 13. Power Dissipation Capacitance
Test Set-Up

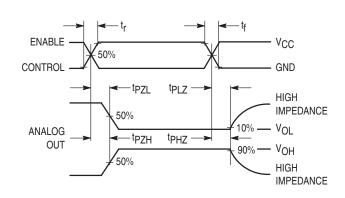
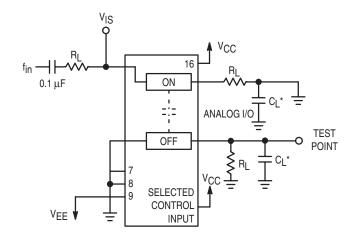
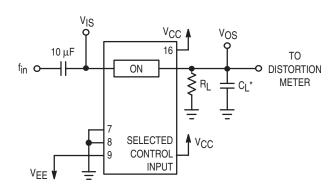


Figure 10. Propagation Delay, ON/OFF Control to Analog Out



\*Includes all probe and jig capacitance.

Figure 12. Crosstalk Between Any Two Switches, Test Set-Up (Adjacent Channels Used)



\*Includes all probe and jig capacitance.

Figure 14. Total Harmonic Distortion, Test Set-Up

#### **APPLICATIONS INFORMATION**

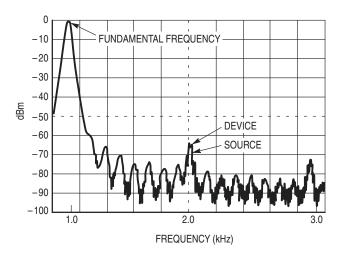


Figure 15. Plot, Harmonic Distortion

The Enable and Control pins should be at V<sub>CC</sub> or GND logic levels, V<sub>CC</sub> being recognized as logic high and GND being recognized as a logic low. Unused analog inputs/outputs may be left floating (not connected). However, it is advisable to tie unused analog inputs and outputs to V<sub>CC</sub> or V<sub>EE</sub> through a low value resistor. This minimizes crosstalk and feedthrough noise that may be picked up by the unused I/O pins.

The maximum analog voltage swings are determined by the supply voltages  $V_{CC}$  and  $V_{EE}$ . The positive peak analog voltage should not exceed  $V_{CC}$ . Similarly, the negative peak analog voltage should not go below  $V_{EE}$ . In the example below, the difference between  $V_{CC}$  and  $V_{EE}$  is twelve volts.

Therefore, using the configuration in Figure 16, a maximum analog signal of twelve volts peak—to—peak can be controlled.

When voltage transients above  $V_{CC}$  and/or below  $V_{EE}$  are anticipated on the analog channels, external diodes (Dx) are recommended as shown in Figure 17. These diodes should be small signal, fast turn—on types able to absorb the maximum anticipated current surges during clipping. An alternate method would be to replace the Dx diodes with Mosorbs (Mosorb<sup>TM</sup> is an acronym for high current surge protectors). Mosorbs are fast turn—on devices ideally suited for precise dc protection with no inherent wear out mechanism.

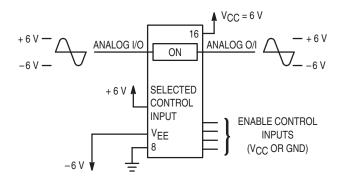


Figure 16.

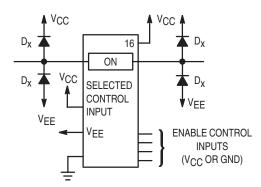


Figure 17. Transient Suppressor Application

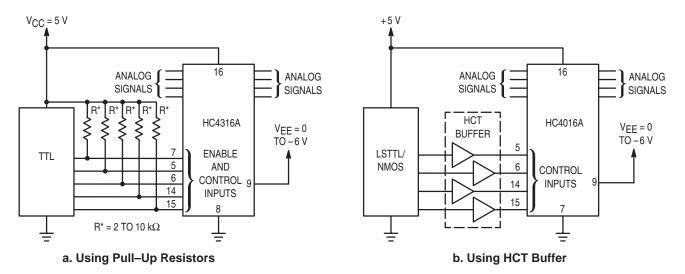


Figure 18. LSTTL/NMOS to HCMOS Interface

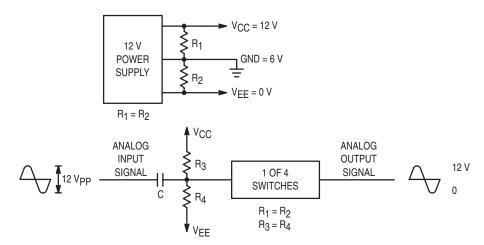


Figure 19. Switching a 0-to-12 V Signal Using a Single Power Supply (GND ≠ 0 V)

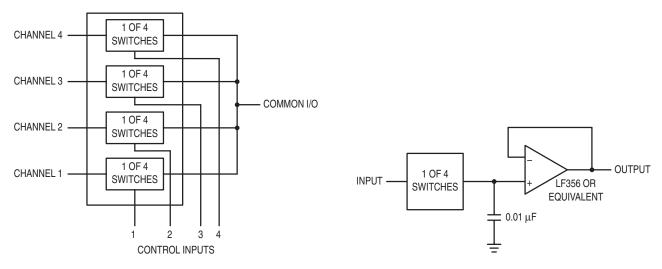
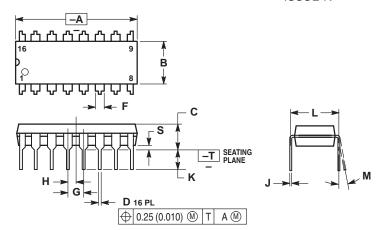


Figure 20. 4-Input Multiplexer

Figure 21. Sample/Hold Amplifier

## **PACKAGE DIMENSIONS**

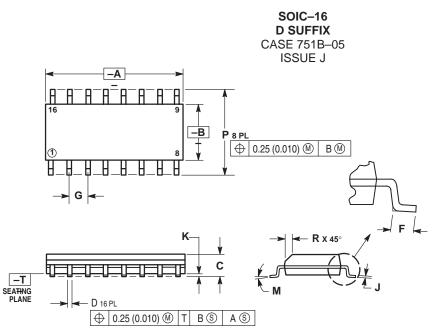
## PDIP-16 **N SUFFIX** CASE 648-08 ISSUE R



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- 1 (4.5)M, 1902.
  2 CONTROLLING DIMENSION: INCH.
  3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
  4. DIMENSION B DOES NOT INCLUDE MOLD FLASH.
- ROUNDED CORNERS OPTIONAL.

	INC	HES	MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.740	0.770	18.80	19.55	
В	0.250	0.270	6.35	6.85	
С	0.145	0.175	3.69	4.44	
D	0.015	0.021	0.39	0.53	
F	0.040	0.070	1.02	1.77	
G	0.	100 BSC	2	.54 BSC	
Н	0.	050 BSC	1	.27 BSC	
J	0.008	0.015	0.21	0.38	
K	0.110	0.130	2.80	3.30	
L	0.295	0.305	7.50	7.74	
M	0°	10°	0°	10°	
S	0.020	0.040	0.51	1.01	



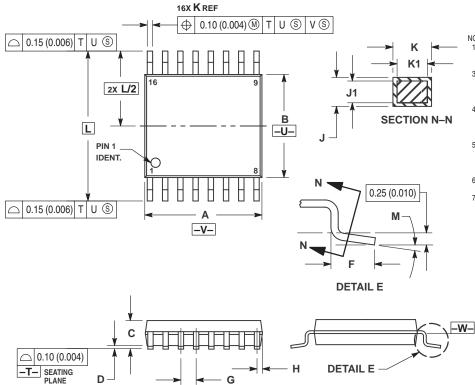
#### NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- Y14.5M, 1982.
  CONTROLLING DIMENSION: MILLIMETER.
  DIMENSIONS A AND B DO NOT INCLUDE
  MOLD PROTRUSION.
  MAXIMUM MOLD PROTRUSION 0.15 (0.006)
- MAXIMUM MOLD PHOLHUSION 0.15 (0.006)
  PER SIDE.
  DIMENSION D DOES NOT INCLUDE DAMBAR
  PROTRUSION. ALLOWABLE DAMBAR
  PROTRUSION SHALL BE 0.127 (0.005) TOTAL
  IN EXCESS OF THE D DIMENSION AT
  MAXIMUM MATERIAL CONDITION.

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	9.80	10.00	0.386	0.393
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.054	0.068
D	0.35	0.49	0.014	0.019
F	0.40	1.25	0.016	0.049
G	1.27 BSC		0.050	) BSC
J	0.19	0.25	0.008	0.009
K	0.10	0.25	0.004	0.009
M	0°	7°	0°	7°
P	5.80	6.20	0.229	0.244
R	0.25	0.50	0.010	0.019

### PACKAGE DIMENSIONS

## TSSOP-16 **DT SUFFIX** CASE 948F-01 **ISSUE O**



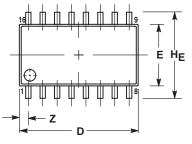
#### NOTES

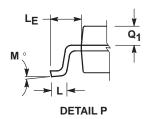
- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A DOES NOT INCLUDE MOLD FLASH. PROTRUSIONS OR GATE BURRS. MOLD FLASH OR 3. GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE
- DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.
- DIMENSION K DOES NOT INCLUDE DAMBAR
  PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.
- TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY
- DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

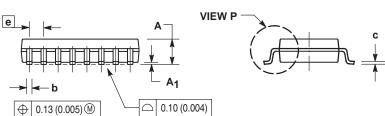
	MILLIMETERS		INC	HES	
DIM	MIN	MAX	MIN	MAX	
Α	4.90	5.10	0.193	0.200	
В	4.30	4.50	0.169	0.177	
C		1.20		0.047	
D	0.05	0.15	0.002	0.006	
F	0.50	0.75	0.020	0.030	
G	0.65 BSC		0.026	BSC	
Н	0.18	0.28	0.007	0.011	
7	0.09	0.20	0.004	0.008	
J1	0.09	0.16	0.004	0.006	
K	0.19	0.30	0.007	0.012	
K1	0.19	0.25	0.007	0.010	
L	6.40		0.252 BSC		
M	0°	8°	0°	8°	

# SOEIAJ-16 **F SUFFIX**

PLASTIC EIAJ SOIC PACKAGE CASE 966-01 **ISSUE O** 







### NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI
  Y14.5M, 1982.
- Y 14.3M, 1982.

  CONTROLLING DIMENSION: MILLIMETER.

  DIMENSIONS D AND E DO NOT INCLUDE

  MOLD FLASH OR PROTRUSIONS AND ARE

  MEASURED AT THE PARTING LINE. MOLD FLASH OR PROTRUSIONS SHALL NOT EXCEED 0.15 (0,006) PER SIDE.
- TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
- THE LEAD WIDTH DIMENSION (b) DOES NOT

INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE LEAD WIDTH DIMENSION AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT. MINIMUM SPACE BETWEEN PROTRUSIONS AND ADJACENT LEAD TO BE 0.46 ( 0.018).

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α		2.05		0.081
A <sub>1</sub>	0.05	0.20	0.002	0.008
b	0.35	0.50	0.014	0.020
С	0.18	0.27	0.007	0.011
D	9.90	10.50	0.390	0.413
Е	5.10	5.45	0.201	0.215
е	1.27 BSC		0.050 BSC	
HE	7.40	8.20	0.291	0.323
L	0.50	0.85	0.020	0.033
LE	1.10	1.50	0.043	0.059
M	0 °	10 °	0 °	10°
Q <sub>1</sub>	0.70	0.90	0.028	0.035
Z		0.78		0.031

# **Notes**

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